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PATENT NUMBER and  
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10063295	FILING DATE 04/09/2002	CLASS 331	SUBCLASS 57	CAU 2817	EXAMINER Shingleton AHS
<b>**APPLICANTS:</b> Abadeer Wagdi; Ellis Wayne; Hansen Patrick; McKenna Jonathan;					
<b>* CONTINUING DATA VERIFIED:</b>					
<b>** FOREIGN APPLICATIONS VERIFIED:</b>					
PG-PUB <input type="checkbox"/> DO NOT PUBLISH <input type="checkbox"/> RESCIND <input type="checkbox"/>					
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no				ATTORNEY DOCKET NO BUR920010127	
TITLE : System and method for measuring circuit performance degradation due to PFET negative bias temperature instability (NBTI)					

U.S. DEPT. OF COMMERCE PAT. & TM. PTO-436L (Rev. 12-94)

<b>NOTICE OF ALLOWANCE MAILED</b>		<b>CLAIMS ALLOWED</b>	
		Total Claims	Print Claims for 0.6
<b>ISSUE FEE</b>		<b>DRAWING</b>	
Amount Due	Date Paid	Sheets Drawg.	Figs. Drawg.
			12
		<b>Application Examiner</b>	
<input type="checkbox"/> <b>TERMINAL DISCLAIMER</b>		<b>PREPARED FOR ISSUE</b>	
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